



TEST REPORT

Application No.: BTEK231116001AE
Applicant: QUANZHOU DAYTECH ELECTRONICS CO., LTD.
Address of Applicant: Hengdali Business Center, North Quanan Road, Jinjiang City, Quanzhou, Fujian, China
Manufacturer: QUANZHOU DAYTECH ELECTRONICS CO., LTD.
Address of Manufacturer: Hengdali Business Center, North Quanan Road, Jinjiang City, Quanzhou, Fujian, China
Factory: QUANZHOU DAYTECH ELECTRONICS CO., LTD.
Address of Factory: Hengdali Business Center, North Quanan Road, Jinjiang City, Quanzhou, Fujian, China
Equipment Under Test (EUT):
EUT Name: Door Sensor
Model No.: DS17BL, DS17WH, DS16BL, DS16WH, DS18BL, DS18WH, DS19BL, DS19WH
Please refer to section 2 of this report which indicates which model was actually tested and which were electrically identical.
Trade Mark: N/A
Standard(s) : 47 CFR Part 2 Subpart J Section 2.1093
Date of Receipt: 2023-11-16
Date of Test: 2023-11-16 to 2023-11-24
Date of Issue: 2023-11-24

Test Result:

Pass*

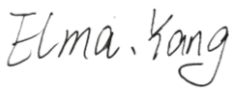
* In the configuration tested, the EUT complied with the standards specified above.

Damon Su

Damon Su
EMC Laboratory Manager



Revision Record				
Version	Chapter	Date	Modifier	Remark
01		2023-11-24		Original

Authorized for issue by				
				
		Elma Yang/ Project Engineer		
				
		Carl Yang /Reviewer		



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General Information

3.1 Details of E.U.T.

Power supply: DC 3V by CR2450 battery(13mA) Max
Cable(s): /
Frequency Range: 433.92MHz
Modulation Type: OOK
Number of Channels: 1
Antenna Type: PCB Antenna
Antenna Gain: 2.78dBi
Hardware Version: MC08-T-V2

Remark: The information in this section is provided by the applicant or manufacturer, BANTEK is not liable to the accuracy, suitability, reliability or/and integrity of the information.

3.2 Description of Support Units

Description	Manufacturer	Model No.	Serial No.
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The EUT has been tested as an independent unit.			



3.3 Test Location

All tests were performed at:

Shenzhen BANTEK Testing Co., Ltd.,

A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street, Bao'an District, Shenzhen, Guangdong, China 518103

Tel:0755-2334 4200

Fax: 0755-2334 4200

FCC Registration Number: 264293

Designation Number: CN1356

No tests were sub-contracted.

3.4 Deviation from Standards

None

3.5 Abnormalities from Standard Conditions

None



4 Test Requirement

KDB447498 D01 General RF Exposure Guidance v06, Clause 4.3.1(a)

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$

Where

-f(GHz) is the RF channel transmit frequency in GHz

-Power and distance are rounded to the nearest mW and mm before calculation

-The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm, and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

4.1 Assessment Result

☒ Passed ☐ Not Applicable

$$E = \text{EIRP} - 20 \log D + 104.8$$

where:

E = electric field strength in dB μ V/m,

EIRP = equivalent isotropic radiated power in dBm

D = specified measurement distance in meters.

Note: Field strength(max)(dB μ V/m) is reference to BTEK231116001AE001

Type	Frequency (MHz)	Field strength(max) (dB μ V/m)	Maximum EIRP (dBm)	Maximum EIRP (mW)	Calculating data	Limit	Result
OOK	433.92	71.55	-23.71	0.0042	0.0005	3.0	Pass

Note: The exposure evaluation safety distance is 5mm.

- End of the Report -

